

FEI Quanta 3D FEG Dual Beam Scanning Electron Microscope (SEM)

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SEM

Availability: by email appointment between 9:30 - 17:30 for a pre-evaluation of the complexity of the tests and estimate of working time.

Conditions of use: exclusively by the responsible specialized staff, mentioned\

Characteristics:

- Operating mode: high vacuum, low vacuum, ESEM
- Detectors: EDT (Everhart Thornlez Detector), LVSED (LowVacuum Secondary Electrons Detector), GSED (Gaseous Secondary Electron Detector)
- Platinum sediment/deposit
- EDX analysis system

Year of purchase: 2010

Upgrade worth 1,070,678 (in situ manipulator and plasma cleaning sistem)

Total amount: 4,263,680 Lei